Application/Control No O9/512,336 Examiner Kin-Chan Chen Applicant(s)/Patent Under Reexamination FUKUDA, SEIICHI Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY			
	Α	US-6,146,542-	11-2000	Ha et al.	216	2
	В	US-6,100,193-	08-2000	Suehiro et al.	438	685
	C.	US-5,164,330-	11-1992	Davis et al.	437	192
	D	US				
	E	US				
	F	US				<u></u>
	G	US		·		
	Н	US		·		
	1	US				
	J	US				
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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